

USBULC6-2F3

2-line Transil[™], transient surge voltage suppressor (TVS) ultralow capacitance protection for high speed USB







Features

- Ultralow diode capacitance (1.5 pF max)
- Two data lines (D+ and D-) protected against ESD

Datasheet - production data

- Breakdown voltage V_{BR} = 6.0 V min.
- Flip Chip, 400 µm pitch, lead-free
- Very low leakage current
- Very small PCB area
- RoHS compliant

Benefits

- Minimized impact on rise and fall times for maximum data integrity
- Low PCB space occupation
- Higher reliability offered by monolithic integration

Complies with the following standards

- IEC 61000-4-2 level 4 on external pins:
 8 kV (contact discharge)
- MIL STD 883G Method 3015.7
 - 25 kV (Human body model)

Application

This device is designed to protect a high speed USB port in wireless handsets (up to 480 Mb/s according to USB 2.0 high speed specification).

Description

The USBULC6-2F3 is a monolithic, application specific discrete device dedicated to ESD protection of high speed interfaces.

Its ultralow line capacitance secures a high level of signal integrity without compromising the protection of downstream sensitive chips against the most stringently characterized ESD strikes.

TM: Transil is a trademark of STMicroelectronics.

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This is information on a product in full production.

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Characteristics 1

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Symbol	Parameter	Value	Unit
V _{PP}	ESD discharge IEC 61000-4-2: Contact discharge	10	kV
P _{PP}	Peak pulse power dissipation (8/20 µs)	90	W
Тj	Maximum junction temperature	125	°C
T _{op}	Operating temperature range	-30 to + 85	°C
T _{stg}	Storage temperature range	-55 to +150	°C





Table 2. Electrical characterist	tics - values (T _{amb}	₅ = 25 °C)
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Symbol	Test conditions	Min.	Тур.	Max.	Unit
V _{BR}	I _R = 1 mA	6	-	9	V
I _{RM}	V _{RM} = 3 V	-	-	70	nA
R _d	Exponential wave form 8/20 μ s, I _{pp} = 1 to 5 A	-	1.2	-	Ω
αΤ	I _R = 1 mA	-	-	5	10 ⁻⁴ / °C
C _{line}	$V_{LINE} = 0 V, V_{OSC} = 30 mV, F = 1 MHz$	-	-	1.5	pF





Figure 3. Eye diagram, board only (according to USB high speed specification)





Figure 5. ESD response to IEC 61000-4-2 (+8 kV contact discharge)⁽¹⁾

Figure 6. ESD response to IEC 61000-4-2 (-8 kV contact discharge)⁽¹⁾



1. Test board connected to oscilloscope through 50 Ω cable and 20 dB + 6 dB attenuator. ESD generator return path connected to PCB ground plane.













Figure 10. Peak pulse power versus initial junction temperature (maximum values, pulse 8/20 µs)



Figure 12. Clamping voltage versus peak pulse current (typical values, pulse 8/20 µs)



Figure 11. Peak pulse power versus exponential pulse duration (maximum values)



Figure 13. Leakage current versus junction temperature (typical values)





2 Application information



3 Ordering information scheme



Figure 15. Ordering information scheme



4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK[®] is an ST trademark.











Figure 19. Tape and reel specifications

Note:

More information is available in the STMicroelectronics Application notes: AN2348: "400 µm Flip Chip: Package description and recommendations for use" AN1751: "EMI Filters: Recommendations and measurements"

5 Ordering information

Order code	Marking	Package	Weight	Base qty	Delivery mode
USBULC6-2F3	EH	Flip Chip	0.91 mg	5000	Tape and reel (7")

Table 3. Ordering information



6 Revision history

Date	Revision	Changes		
15-Dec-2006	1	Initial release.		
29-Apr-2008	2	Updated ECOPACK statement. Updated <i>Figure 16</i> , <i>Figure 17</i> and <i>Figure 19</i> . Reformatted to current standards.		
27-Jun-2011	3	Added <i>Figure 5</i> and <i>Figure 6</i> . Updated die dimensions in <i>Figure 16</i> and pocket dimensions in <i>Figure 19</i> .		
31-Mar-2014	4	Updated bump-side Pin 1 dot in <i>Figure</i> and <i>Figure</i> 16. Updated value of C _{line} in <i>Table</i> 2. Removed graphics on 15 kV ESD responses and digital crosstalk. Updated Figures 3 through 13. Corrected graphical error in <i>Figure</i> 19		

Table 4. Document revision history



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